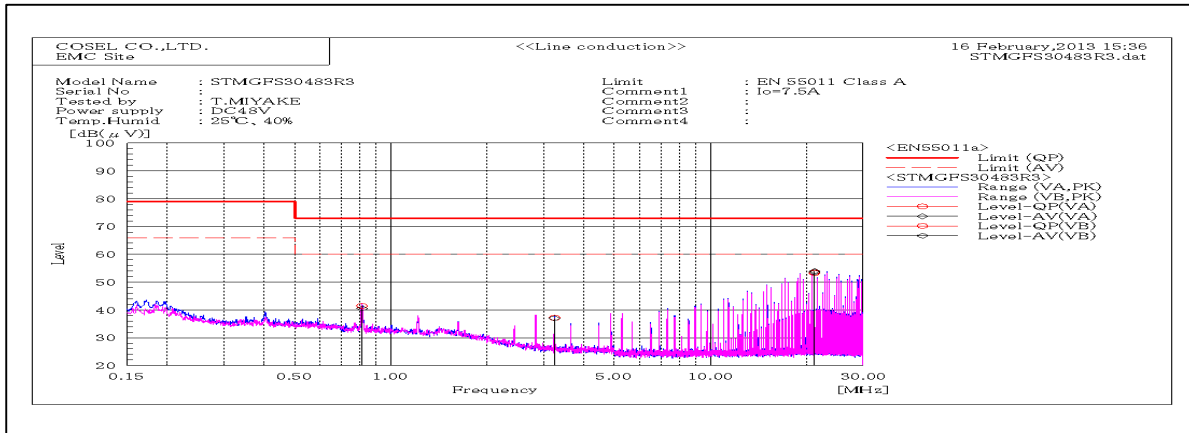
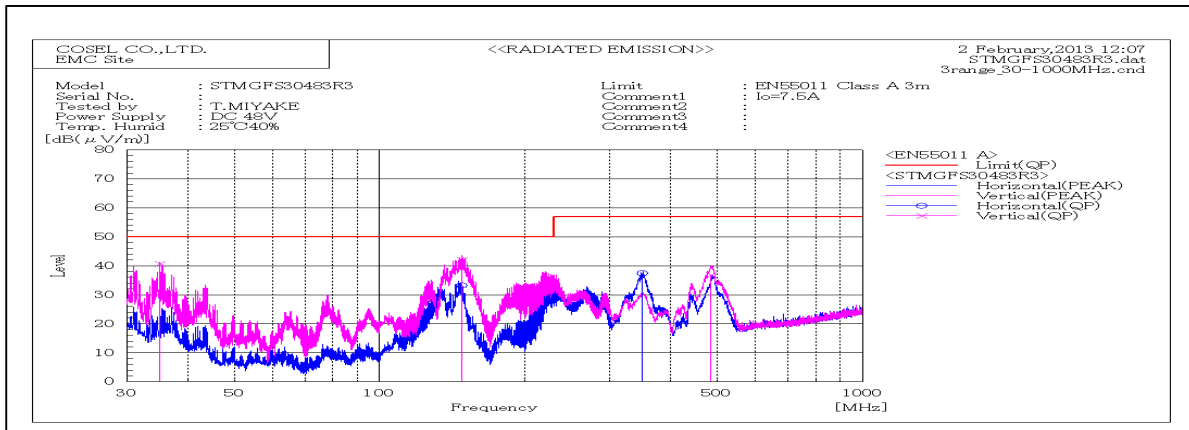


DATA SHEET		Date	18-Feb-13
Model	STMGFS30483R3	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	T.Miyake



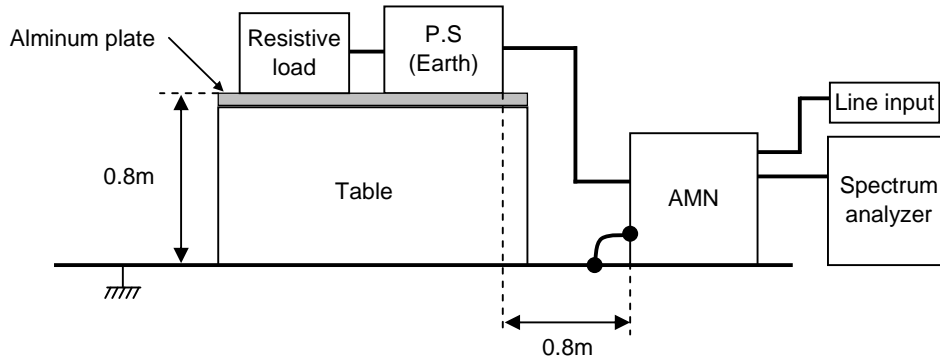
Frequency MHz	Harm	Line Phase	Reading dB(uV)		Factor dB	Level dB(uV)		Limit dB(uV)		Margin dB		Pass/Fail	Remark
			QP	AV		QP	AV	QP	AV	QP	AV		
0.81325		VB	21.4	20.4	20.1	41.5	40.5	73	60	31.5	19.5	Pass	
3.25211		VA	16.8	16.6	20.4	37.2	37	73	60	35.8	23	Pass	
21.13695		VB	32.1	32.4	21.2	53.3	53.6	73	60	19.7	6.4	Pass	
21.13625		VA	32.4	32.7	21.2	53.6	53.9	73	60	19.4	6.1	Pass	



Frequency MHz	Polarization	Stability	Reading dB(uV)		Space Loss dB	Level dB(mW)		Limit dB(mW)	Margin dB	Pass/Fail	Height cm	Angle deg	Remark
			QP			QP							
35.044	V	Stable	55.5		-14.9	40.6	50	9.4	Pass	102	168		
147.929	V	Stable	59.8		-17.8	42	50	8	Pass	110	299		
147.924	H	Stable	53.6		-20.3	33.3	50	16.7	Pass	156	242		
350.054	H	Stable	50.6		-13.2	37.4	57	19.6	Pass	103	84		
485.679	V	Stable	49.3		-12.5	36.8	57	20.2	Pass	135	331		

DATA SHEET		Date	18-Feb-13
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	T.Miyake

1. Line conduction



2. Radiated emission

